



# Workshop

## Simulation and Characterization of Statistical CMOS Variability and Reliability

8th-9th September 2010, Bologna, Italy  
Royal Hotel Carlton, Via Montebello, 8  
40121 Bologna, Italy

### Programme

#### 8th Sept:

17.30: Registration and Poster Session

#### 9th Sept:

8.30: Introduction

Impact of Statistical Variability and Reliability on Circuit Design - *S. Nassif (IBM)*

9.00: TCAD Simulation of Statistical Variability

*A. Brown - University of Glasgow (UK)*

*V. Moroz - Synopsys (USA)*

*S. Toriyama - Toshiba (Japan)*

10.15: Coffee Break

10.45: Measurements and Characterisation of Statistical Variability

*C. Spanos - University of California, Berkeley (USA)*

*G. Ghibaudo - IMEP/MINATEC (France)*

*T. Hiramoto - Tokyo University (Japan)*

12.00: Buffet Lunch + Interactive Presentations from TCAD Vendors

13.30: Reliability Impact and Scaling Trends

*Y. Cao - Arizona State University (USA)*

*K. Takeuchi - Renesas Electronics (Japan)*

*T. Grasser - Technical University Vienna (Austria)*

14.45: Coffee Break

15.00: Statistical Compact Model Strategies and Statistical Circuit Simulation

*M. Miura-Mattaush - Hiroshima University (Japan)*

*J. Victory - Sentinel (USA)*

*A. Juge - ST Microelectronics (France)*

16.15: Closing Address:

Interaction Between TCAD, Compact Models and Circuit Simulation to Support Statistical and Robust Design - *A. Asenov (University of Glasgow)*

16:45: Close

**Posters:** All registered participants are invited to present a poster highlighting interesting results in the Workshop area. Please indicate your intention to present a poster by e-mailing a 1/2 page abstract to [A.Asenov@elec.gla.ac.uk](mailto:A.Asenov@elec.gla.ac.uk).

**Registration:** The registration fee of €100 is payable together with the SISPAD registration.

Workshop Organisers: *A. Asenov (University of Glasgow), S. Nassif (IBM) and G. Baccarani (University of Bologna)*



Sponsors

